International IOR Rectifier

POWER MOSFET THRU-HOLE (TO-257AA)

IRFY340C, IRFY340CM 400V, N-CHANNEL

HEXFET® MOSFET TECHNOLOGY

Product Summary

Part Number	RDS(on)	ΙD	Eyelets		
IRFY340C	$0.55~\Omega$	8.7A	Ceramic		
IRFY340CM	0.55 Ω	8.7A	Ceramic		

HEXFET® MOSFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.



Features:

- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed
- Electrically Isolated
- Ceramic Eyelets
- Ideally Suited For Space Level **Applications**

Absolute Maximum Ratings

	Parameter	- Lab (1997)	Units
ID @ VGS = 10V, TC = 25°C Continuous Drain Current		8.7	
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current	5.5	Α
IDM	Pulsed Drain Current ①	35	
P _D @ T _C = 25°C	Max. Power Dissipation	100	W
	Linear Derating Factor	0.8	W/°C
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	520	mJ
IAR	Avalanche Current ①	8.7	Α
EAR Repetitive Avalanche Energy ①		10	mJ
dv/dt Peak Diode Recovery dv/dt 3		4.0	V/ns
TJ	Operating Junction	-55 to 150	
TSTG	Storage Temperature Range		°C
找了PDF	Lead Temperature	300(0.063in./1.6mm from case for 10 sec)	
组库——	Weight	4.3 (Typical)	g

For footnotes refer to the last page

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

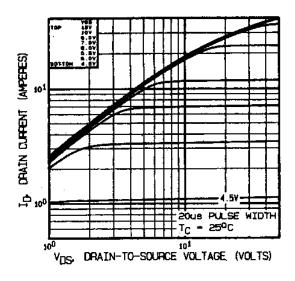
	Parameter	Min	Тур	Max	Units	Test Conditions
BVDSS	Drain-to-Source Breakdown Voltage	400	_	_	V	VGS = 0V, ID = 1.0mA
ΔBVDSS/ΔTJ	Temperature Coefficient of Breakdown Voltage	_	0.46	_	V/°C	Reference to 25°C, I _D = 1.0mA
RDS(on)	Static Drain-to-Source On-State Resistance	_	_	0.55	Ω	VGS = 10V, ID = 5.5A _④
VGS(th)	Gate Threshold Voltage	2.0	_	4.0	V	VDS = VGS, ID = 250μA
9fs	Forward Transconductance	4.9	_	_	S (7)	V _{DS} > 15V, I _{DS} = 5.5A ④
IDSS	Zero Gate Voltage Drain Current		_	25	μА	VDS= 320V ,VGS=0V
		_	_	250	μΑ	VDS = 320V,
						VGS = 0V, TJ = 125°C
IGSS	Gate-to-Source Leakage Forward	_	_	100	^	VGS = 20V
IGSS	Gate-to-Source Leakage Reverse	_	_	-100	nA	VGS = -20V
Qg	Total Gate Charge	_	_	65		VGS =10V, ID = 8.7A
Qgs	Gate-to-Source Charge	_	_	10	nC	VDS = 200V
Qgd	Gate-to-Drain ('Miller') Charge	_	_	40.5		
td(on)	Turn-On Delay Time	_	_	25		$V_{DD} = 200V, I_{D} = 8.7A,$
tr	Rise Time	_	_	92	ns	$RG = 9.1\Omega$
td(off)	Turn-Off Delay Time	_	_	79	115	
tf	Fall Time		_	58		
LS+LD	Total Inductance	_	6.8	_	nΗ	Measured from drain lead (6mm/0.25in. from package) to source lead (6mm/0.25in. from
						package)
Ciss	Input Capacitance		1400	_		VGS = 0V, VDS = 25V
Coss	Output Capacitance		350	_	pF	f = 1.0MHz
C _{rss}	Reverse Transfer Capacitance	_	230	_		

Source-Drain Diode Ratings and Characteristics

	Parameter		Min	Тур	Max	Units	Test Conditions
Is	Continuous Source Current (Body Diode)		_	_	8.7	۸	
ISM	Pulse Source Current (Body	Diode) ①	_	_	35	Α	
VSD	Diode Forward Voltage		_	_	1.5	V	$T_j = 25^{\circ}C$, $I_S = 8.7A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		_	_	600	nS	T_j = 25°C, I_F = 8.7A, di/dt ≤ 100A/μs
QRR	Reverse Recovery Charge		_	_	5.6	μC	V _{DD} ≤ 50V ④
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by LS + LD.					

Thermal Resistance

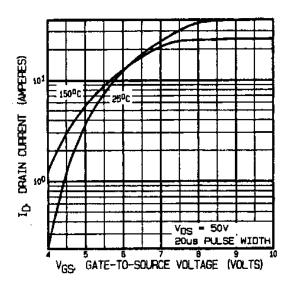
	Parameter	Min	Тур	Max	Units	Test Conditions
RthJC	Junction-to-Case	_	_	1.25		
RthCS	Case-to-sink	_	0.21	_	°C/W	
RthJA	Junction-to-Ambient	_	_	80		Typical socket mount



VDS. DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



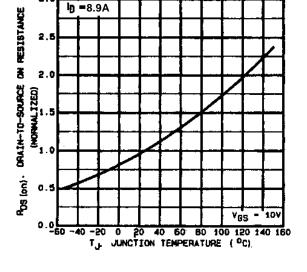


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance Vs. Temperature

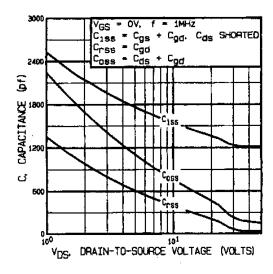
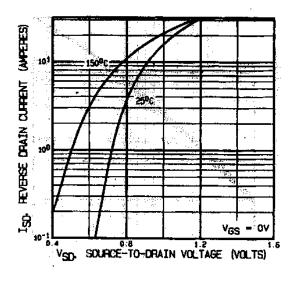


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage



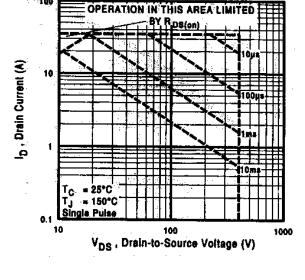


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area

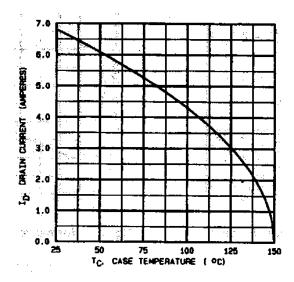


Fig 9. Maximum Drain Current Vs. Case Temperature

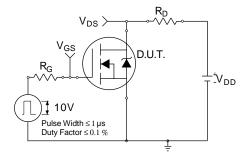


Fig 10a. Switching Time Test Circuit

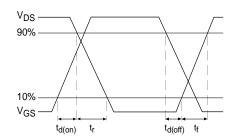


Fig 10b. Switching Time Waveforms

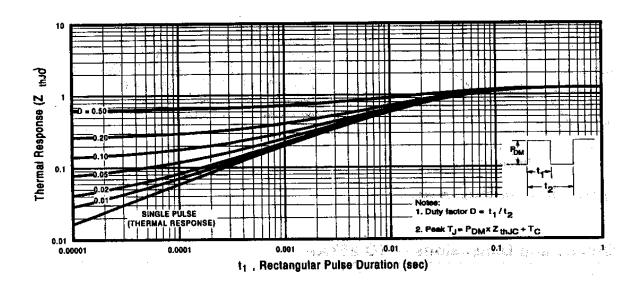


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

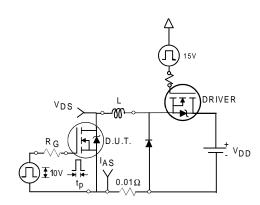


Fig 12a. Unclamped Inductive Test Circuit

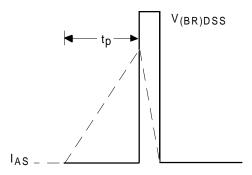


Fig 12b. Unclamped Inductive Waveforms

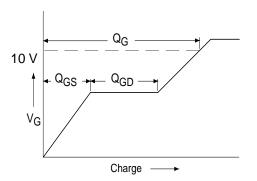


Fig 13a. Basic Gate Charge Waveform

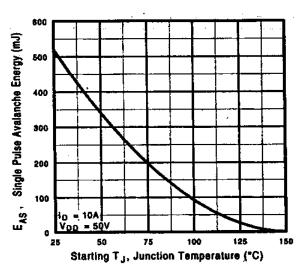


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

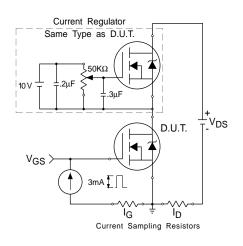


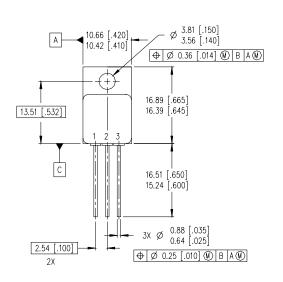
Fig 13b. Gate Charge Test Circuit

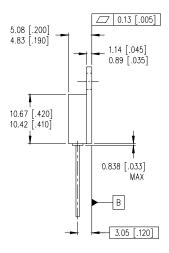
Footnotes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② $V_{DD} = 50V$, starting $T_J = 25$ °C, L = 13mH Peak I_I = 8.7A, $V_{GS} = 10V$

- ③ ISD ≤ 8.7A, di/dt ≤ 120A/ μ s, $V_{DD} \le 400V$, $T_J \le 150$ °C
- 4 Pulse width $\leq 300 \ \mu s$; Duty Cycle $\leq 2\%$

Case Outline and Dimensions — TO-257AA



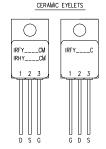


NOTES:

- 1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1994.
- 2. CONTROLLING DIMENSION: INCH.
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE TO-257AA.

LEGEND D - DRAIN S - SOURCE

G - GATE





IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903